SN54HC4002, SN74HC4002 DUAL 4-INPUT POSITIVE-NOR GATES

SCLS157

D2684, DECEMBER 1982-REVISED SEPTEMBER 1987

- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil
- Dependable Texas Instruments Quality and Reliability

description

These devices contain two independent 4-input positive NOR gates. They perform the Boolean functions:

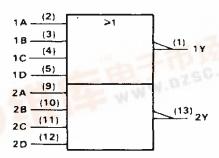
 $Y = \overline{A} + \overline{B} + \overline{C} + \overline{D}$ or $Y = \overline{A} \cdot \overline{B} \cdot \overline{C} \cdot \overline{D}$ in positive logic.

The SN54HC4002 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74HC4002 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE

	INP	UTS		OUTPUT
Α	В	С	D	Y
Н	Х	Х	Х	
Х	Н	Х	Х	L
х	X	H	X) L
Х	X	Х	Н	L
L	L	L	L	Н

logic symbol[†]

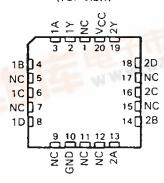


 $^{^\}dagger$ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

SN54HC4002 . . . J PACKAGE SN74HC4002 . . . D OR N PACKAGE (TOP VIEW)

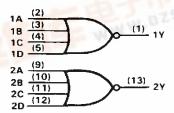
1Y 🗌	1	V[4] V	CC
1A 🗌	2	13 2	Υ
18 🗌	3	12 2	D
1C 🗌	4	11 2	С
1D [5	10 2	В
NC 🗌	6	9 🗍 2	Α
GND 🗌	7	8] N	C

SN54HC4002 . . . FK PACKAGE (TOP VIEW)



NC-No internal connection

logic diagram (positive logic)



Pin numbers shown are for D, J, and N packages.

absolute maximum ratings over operating free-air temperature range[†]

Supply voltage range, VCC0.5 V to 7 V
Input clamp current, IjK (VI < 0 or VI > VCC) ± 20 mA
Output clamp current, IOK (VO < 0 or VO > VCC)
Continuous output current, IO (VO = 0 to VCC) ± 25 mA
Continuous current through VCC or GND pins
Lead temperature 1,6 mm (1/16 in) from case for 60 s: FK or J package
Lead temperature 1,6 mm (1/16 in) from case for 10 s: D or N package
Storage temperature range65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

			SN54HC4002		SN74HC4002			UNIT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage		2	5	6	2	5	6	>
		V _{CC} = 2 V	1.5			1.5			
V_{IH}	High-level input voltage	V _{CC} = 4.5 V	3.15			3.15			V
		V _{CC} = 6 V	4.2	_		4.2			
		V _{CC} = 2 V	0		0.3	0		0.3	
V_{IL}	Low-level input voltage	V _{CC} = 4.5 V	0		0.9	0		0.9	V
		V _{CC} = 6 V	0		1.2	0		1.2	
VI	Input voltage		0		Vcc	0		Vcc_	V
Vo	Output voltage		0		Vcc	0		VCC	V
		V _{CC} = 2 V	0		1000	0		1000	
tt	Input transition (rise and fall) times	$V_{CC} = 4.5 \text{ V}$	0		500	0		500	ns
-		V _{CC} = 6 V	0		400	0		400	
TΑ	Operating free-air temperature		- 55		125	-40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	TEST COMPITIONS	TA = 25°C		SN54HC4002		SN74HC4002		UNIT		
PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	
		2 V	1.9	1.998		1.9		1.9		
Ì	$V_{\parallel} = V_{\parallel H}$ or $V_{\parallel L}$, $I_{OH} = -20 \mu A$	4.5 V	4.4	4.499		4.4		4.4		v
∨он	<u> </u>	6 V	5.9	5.999		5.9		5.9		
	$V_{I} = V_{IH} \text{ or } V_{IL}, I_{OH} = -4 \text{ mA}$	4.5 V	3.98	4.30		3.7		3.84		
	$V_{\parallel} = V_{\parallel H}$ or $V_{\parallel L}$, $I_{OH} = -5.2$ mA	6 V	5.48	5.80		5.2		5.34		l
		2 V		0.002	0.1		0.1		0.1	
	$V_{\parallel} = V_{\parallel H}$ or $V_{\parallel L}$, $I_{\rm OL} = 20 \mu A$	4.5 V		0.001	0.1		0.1	[0.1	
VoL		6 V 0.001	0.001	0.1		0.1		0.1	٧	
	VI = VIH or VIL, IOL = 4 mA	4.5 V	4.5 V 0.17 0.26 0.4		0.33	1				
	VI = VIH or VIL, IOL = 5.2 mA	6 V		0.15	0.26		0.4		0.33	
1	V _I = V _{CC} or 0	6 V		±0.1	±100		± 1000	3	1000	nΑ
lcc	$V_I = V_{CC}$ or 0, $I_{O} = 0$	6 V			2		40	[20	μΑ
Ci		2 to 6 V		3	10		10		10	pF

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switching characteristics over recommended operating free-air temperature range (unless otherwise noted), $C_L = 50 \text{ pF}$ (see Note 1)

DADAMSTED	FROM	то		TA = 25°C			SN54HC4002		SN74HC4002		UNIT
PARAMETER	(INPUT)	(OUTPUT)	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
	<u> </u>		2 V		44	110		165		140	
t _{pd}	A thru D	Y	4.5 V		12	22		33		28	กร
.			6 V	1	11	19		28		24	
			2 V		38	75		110		95	
tt		Y	4.5 V		8	15		22		19	ns
			6 V	1	6	13	1	19		16	

	Power dissipation capacitance per gate	No load, TA = 25°C	25 pF typ
∼pd	1 over dissipation capacitatice per gate	140 load, 1A - 25 O	20 p. typ

Note 1: Load circuits and voltage waveforms are shown in Section 1.

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